

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,930,862 B2
DATED : August 16, 2005
INVENTOR(S) : Gill et al.

Page 1 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page.

Item [56], **References Cited**, U.S. PATENT DOCUMENTS, add the following patent numbers:

-- 6,117,690
5,965,283
5,699,215
5,422,621
4,371,905
4,935,832 --.

FOREIGN PATENT DOCUMENTS, add the following publication number:

-- WO 01/41214 A1 06/2001 WIPO 23/58 --.

OTHER PUBLICATIONS, add the following citations:

-- Solin, S.A. et al; Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors, SCIENCE Vol. 289, 09/01/2000.

Solin, S.A. et al; Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors, The Magnetic Recording Conference, August 20-22, 2001.

Isai, Masaaki et al; Preparation and Crystal Properties of Thin InSb Films for Highly Sensitive Magnetoresistance Elements, Journal of Materials Research, 1986. --.

Chi, C. et al; Gradiometer Hall Probe, IBM Technical Disclosure Bulletin, Vol. 37 04/1994.

Gambino, R. et al; Improved Magnetoresistive Sensor, IBM Technical Disclosure Bulletin, Vol. 38, No. 08, August 1995.

Gambino, R. et al; Magnetic Films for Hall Effect Devices Useful for Magnetic Recording Heads, IBM Technical Disclosure Bulletin, Vol. 18, No. 12, May 1976. --.

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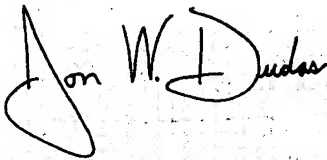
Page 2 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 8,
Line 9, after "of the EMR" delete "read".

Signed and Sealed this

Thirteenth Day of December, 2005

A handwritten signature in black ink, reading "Jon W. Dudas", is written over a faint, rectangular grid background.

JON W. DUDAS
Director of the United States Patent and Trademark Office